




<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10749240</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>AHN, KIL-JAE</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
180	277	10/27/2006	HK
180	279	10/27/2006	HK
180	326	10/27/2006	HK

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<b>Search Notes</b>  	Application/Control No.  10749240	Applicant(s)/Patent Under Reexamination  AHN, KIL-JAE
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
74/\$ (no search) (consulted David Fenstermacher)	10/27/2006	HK
180/271,277,279,282 (consulted Faye Fleming)	06/13/2006	HK
180/326+ (consulted Brian Circus)	10/27/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/27/2006	HK
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